

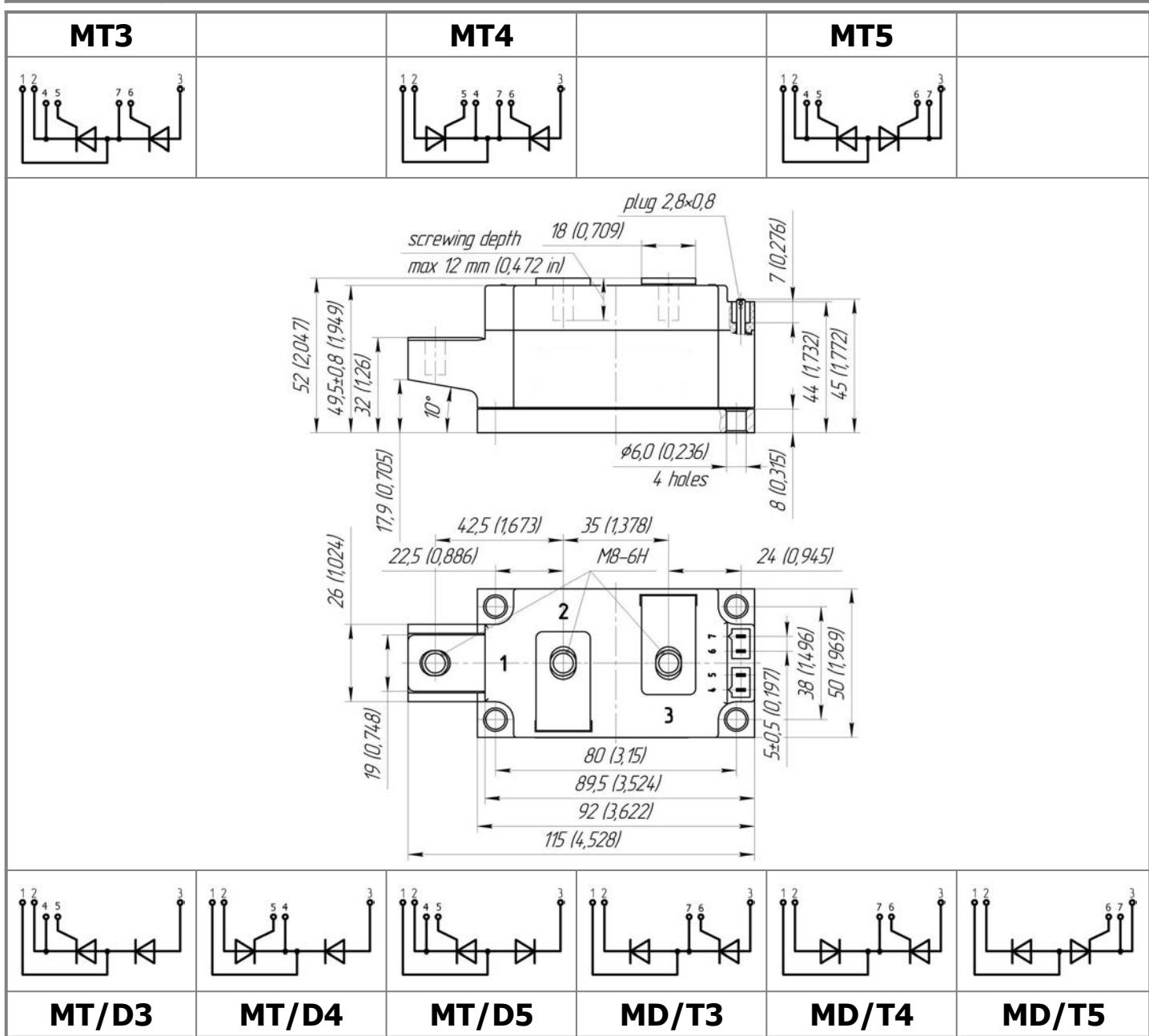


# Thyristor Modules

## MTx-200-28-C1



Mean on-state current	$I_{TAV}$	200 A
Repetitive peak off-state voltage	$V_{DRM}$	2600...2800 V
Repetitive peak reverse voltage	$V_{RRM}$	
Turn-off time	$t_{qf}$	250 $\mu$ s
$V_{DRM}, V_{RRM}, V$	2600	2800
Voltage code	26	28
$T_j, ^\circ C$	-40...+125	



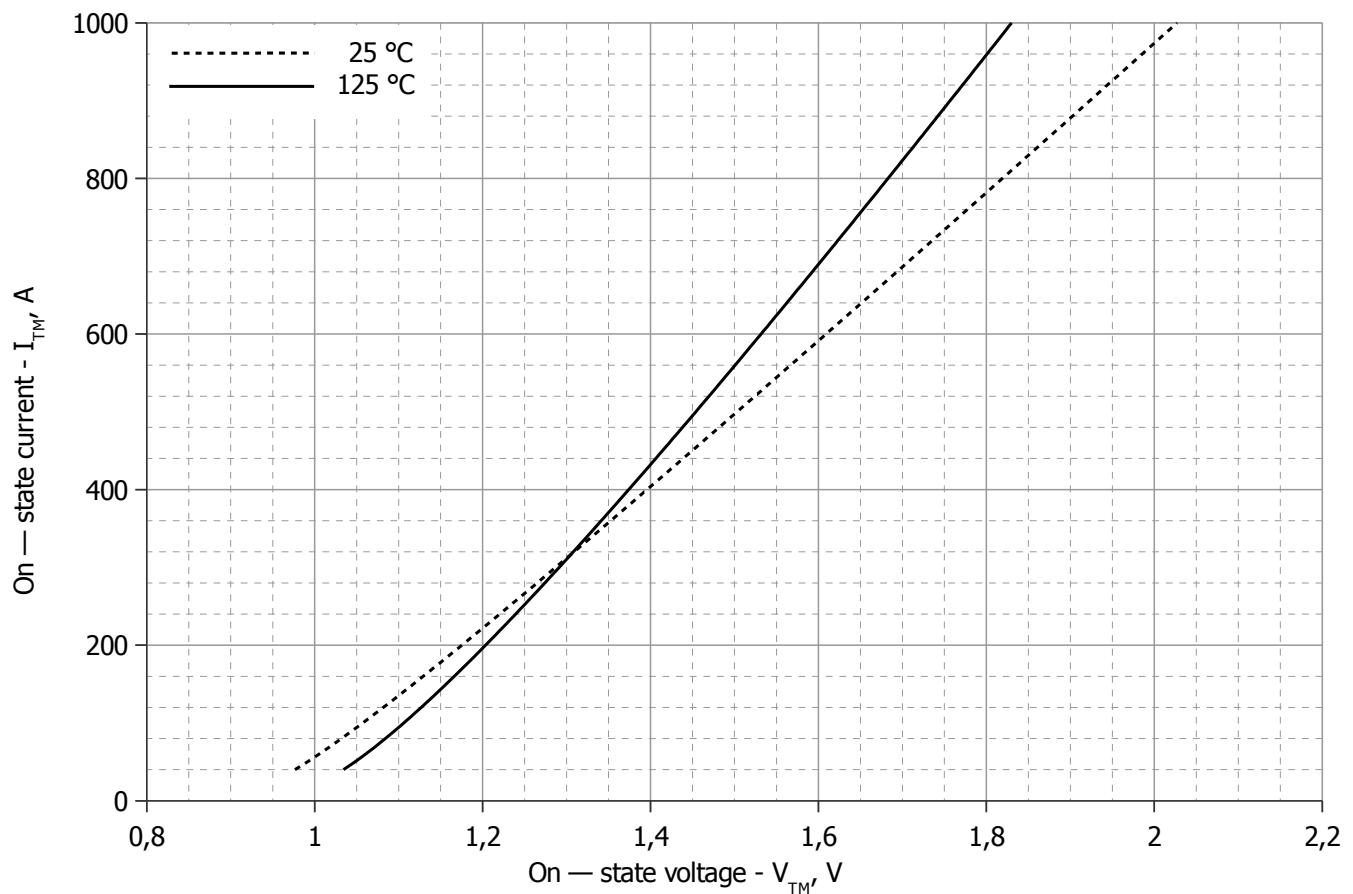
# MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions	
<b>ON-STATE</b>					
$I_{TAV}$	Maximum allowable mean on-state current	A	200 305	$T_c=101^\circ\text{C}$ ; $T_c=85^\circ\text{C}$ ; 180° half-sine wave; 50 Hz	
$I_{TRMS}$	RMS on-state current	A	314	$T_c=101^\circ\text{C}$ ; 180° half-sine wave; 50 Hz	
$I_{TSM}$	Surge on-state current	kA	6.5 7.5	$T_j=T_{j \max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; $t_p=10\text{ ms}$ ; single pulse; $V_D=V_R=0\text{ V}$ ; Gate pulse: $I_G=2\text{ A}$ ; $t_{GP}=50\text{ }\mu\text{s}$ ; $di_G/dt \geq 1\text{ A}/\mu\text{s}$
			7.0 8.0	$T_j=T_{j \max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; $t_p=8.3\text{ ms}$ ; single pulse; $V_D=V_R=0\text{ V}$ ; Gate pulse: $I_G=2\text{ A}$ ; $t_{GP}=50\text{ }\mu\text{s}$ ; $di_G/dt \geq 1\text{ A}/\mu\text{s}$
$I^2t$	Safety factor	$\text{A}^2\text{s} \cdot 10^3$	210 280	$T_j=T_{j \max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; $t_p=10\text{ ms}$ ; single pulse; $V_D=V_R=0\text{ V}$ ; Gate pulse: $I_G=2\text{ A}$ ; $t_{GP}=50\text{ }\mu\text{s}$ ; $di_G/dt \geq 1\text{ A}/\mu\text{s}$
			200 260	$T_j=T_{j \max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; $t_p=8.3\text{ ms}$ ; single pulse; $V_D=V_R=0\text{ V}$ ; Gate pulse: $I_G=2\text{ A}$ ; $t_{GP}=50\text{ }\mu\text{s}$ ; $di_G/dt \geq 1\text{ A}/\mu\text{s}$
<b>BLOCKING</b>					
$V_{DRM}, V_{RRM}$	Repetitive peak off-state and Repetitive peak reverse voltages	V	2600...2800	$T_{j \min} < T_j < T_{j \max}$ ; 180° half-sine wave; 50 Hz; Gate open	
$V_{DSM}, V_{RSM}$	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	2700...2900	$T_{j \min} < T_j < T_{j \max}$ ; 180° half-sine wave; single pulse; Gate open	
$V_D, V_R$	Direct off-state and Direct reverse voltages	V	$0.6 \cdot V_{DRM}$ $0.6 \cdot V_{RRM}$	$T_j=T_{j \max}$ ; Gate open	
<b>TRIGGERING</b>					
$I_{FGM}$	Peak forward gate current	A	6	$T_j=T_{j \max}$	
$V_{RGM}$	Peak reverse gate voltage	V	5		
$P_G$	Gate power dissipation	W	3	$T_j=T_{j \max}$ for DC gate current	
<b>SWITCHING</b>					
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive ( $f=1\text{ Hz}$ )	$\text{A}/\mu\text{s}$	1250	$T_j=T_{j \max}$ ; $V_D=0.67 \cdot V_{DRM}$ ; $I_{TM}=1300\text{ A}$ ; Gate pulse: $I_G=2\text{ A}$ ; $t_{GP}=50\text{ }\mu\text{s}$ ; $di_G/dt \geq 2\text{ A}/\mu\text{s}$	
<b>THERMAL</b>					
$T_{stg}$	Storage temperature	$^\circ\text{C}$	-40...+50		
$T_j$	Operating junction temperature	$^\circ\text{C}$	-40...+125		
$T_{c op}$	Operating temperature	$^\circ\text{C}$	-40...+125		
<b>MECHANICAL</b>					
a	Acceleration under vibration	$\text{m/s}^2$	50		

## CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions		
<b>ON-STATE</b>						
V <sub>TM</sub>	Peak on-state voltage, max	V	1.80	T <sub>j</sub> =25 °C; I <sub>TM</sub> = 785 A		
V <sub>T(TO)</sub>	On-state threshold voltage, max	V	1.061	T <sub>j</sub> =T <sub>j</sub> max;		
r <sub>T</sub>	On-state slope resistance, max	mΩ	0.772	0.5 π I <sub>TAV</sub> < I <sub>T</sub> < 1.5 π I <sub>TAV</sub>		
I <sub>L</sub>	Latching current, max	mA	700	T <sub>j</sub> =25 °C; V <sub>D</sub> =12 V; Gate pulse: I <sub>G</sub> =2 A; t <sub>GP</sub> =50 μs; di <sub>G</sub> /dt≥1 A/μs		
I <sub>H</sub>	Holding current, max	mA	300	T <sub>j</sub> =25 °C; V <sub>D</sub> =12 V; Gate open		
<b>BLOCKING</b>						
I <sub>DRM</sub> , I <sub>RRM</sub>	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	50 2.50	T <sub>j</sub> =T <sub>j</sub> max T <sub>j</sub> = 25 °C	V <sub>D</sub> =V <sub>DRM</sub> ; V <sub>R</sub> =V <sub>RRM</sub>	
(dv <sub>D</sub> /dt) <sub>crit</sub>	Critical rate of rise of off-state voltage <sup>1)</sup> , min	V/μs	200, 320, 500, 1000, 1600, 2000, 2500	T <sub>j</sub> =T <sub>j</sub> max; V <sub>D</sub> =0.67·V <sub>DRM</sub> ; Gate open		
<b>TRIGGERING</b>						
V <sub>GT</sub>	Gate trigger direct voltage, max	V	3.00 2.00 1.50	T <sub>j</sub> = T <sub>j</sub> min T <sub>j</sub> =25 °C T <sub>j</sub> = T <sub>j</sub> max	V <sub>D</sub> =12 V; I <sub>D</sub> =3 A; Direct gate current	
I <sub>GT</sub>	Gate trigger direct current, max	mA	250 150 150	T <sub>j</sub> = T <sub>j</sub> min T <sub>j</sub> = 25 °C T <sub>j</sub> = T <sub>j</sub> max		
V <sub>GD</sub>	Gate non-trigger direct voltage, min	V	0.60	T <sub>j</sub> =T <sub>j</sub> max; V <sub>D</sub> =0.67·V <sub>DRM</sub> ;		
I <sub>GD</sub>	Gate non-trigger direct current, min	mA	35.00	Direct gate current		
<b>SWITCHING</b>						
t <sub>gd</sub>	Delay time, max	μs	1.85	T <sub>j</sub> =25 °C; V <sub>D</sub> =1500 V; I <sub>TM</sub> =I <sub>TAV</sub> ; di/dt=200 A/μs;	Gate pulse: I <sub>G</sub> =2 A; V <sub>G</sub> =20 V; t <sub>GP</sub> =50 μs; di <sub>G</sub> /dt=2 A/μs	
t <sub>gt</sub>	Turn-on time, max	μs	9.00			
t <sub>q</sub>	Turn-off time <sup>2)</sup> , max	μs	250	dv <sub>D</sub> /dt=50 V/μs; T <sub>j</sub> =T <sub>j</sub> max; I <sub>TM</sub> = I <sub>TAV</sub> ; di <sub>R</sub> /dt=-10 A/μs; V <sub>R</sub> =100V; V <sub>D</sub> =0.67 V <sub>DRM</sub>		
Q <sub>rr</sub>	Total recovered charge, max	μC	1170	T <sub>j</sub> =T <sub>j</sub> max; I <sub>TM</sub> =200 A;		
t <sub>rr</sub>	Reverse recovery time, max	μs	24	di <sub>R</sub> /dt=-10 A/μs;		
I <sub>rr</sub>	Reverse recovery current, max	A	97	V <sub>R</sub> =100 V		
<b>THERMAL</b>						
R <sub>thjc</sub>	Thermal resistance, junction to case			180° half-sine wave, 50 Hz		
	per module	°C/W	0.0400			
	per arm	°C/W	0.0800			
R <sub>thch</sub>	Thermal resistance, case to heatsink					
	per module	°C/W	0.0200			
	per arm	°C/W	0.0400			
<b>INSULATION</b>						
V <sub>ISOL</sub>	Insulation test voltage	kV	3.00	Sine wave, 50 Hz;		
			3.60	RMS t=60 sec		
<b>MECHANICAL</b>						
M <sub>1</sub>	Mounting torque (M6) <sup>3)</sup>	Nm	6.00	Tolerance ± 15%		
M <sub>2</sub>	Terminal connection torque (M8) <sup>3)</sup>	Nm	9.00	Tolerance ± 15%		
m	Weight, max	g	860			

PART NUMBERING GUIDE								NOTES																							
MT 3 - 200 - 28 - A2 M2 - C1 - N								1) Critical rate of rise of off-state voltage																							
1	2	3	4	5	6	7	8	<table border="1"> <thead> <tr> <th>Symbol of Group (dv<sub>D</sub>/dt)<sub>crt</sub>, V/μs</th> <th>P2</th> <th>K2</th> <th>E2</th> <th>A2</th> <th>T1</th> <th>P1</th> <th>M1</th> </tr> </thead> <tbody> <tr> <td>200</td> <td>320</td> <td>500</td> <td>1000</td> <td>1600</td> <td>2000</td> <td>2500</td> <td></td> </tr> </tbody> </table>								Symbol of Group (dv <sub>D</sub> /dt) <sub>crt</sub> , V/μs	P2	K2	E2	A2	T1	P1	M1	200	320	500	1000	1600	2000	2500	
Symbol of Group (dv <sub>D</sub> /dt) <sub>crt</sub> , V/μs	P2	K2	E2	A2	T1	P1	M1																								
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1. Thyristor module (MT)								2) Turn-off time (dv <sub>D</sub> /dt=50 V/μs)																							
Thyristor – Diode module (MT/D)								<table border="1"> <thead> <tr> <th>Symbol of Group</th> <th>M2</th> </tr> </thead> <tbody> <tr> <td>t<sub>q</sub>, μs</td> <td>250</td> </tr> </tbody> </table>								Symbol of Group	M2	t <sub>q</sub> , μs	250												
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Diode – Thyristor module (MD/T)								3) The screws must be lubricated																							
2. Circuit Schematic																															
3. Average On-state Current, A																															
4. Voltage Code																															
5. Critical rate of rise of off-state voltage																															
6. Group of turn-off time (dv <sub>D</sub> /dt=50 V/μs)																															
7. Package Type (M.C1)																															
8. Ambient Conditions:																															
N – Normal																															



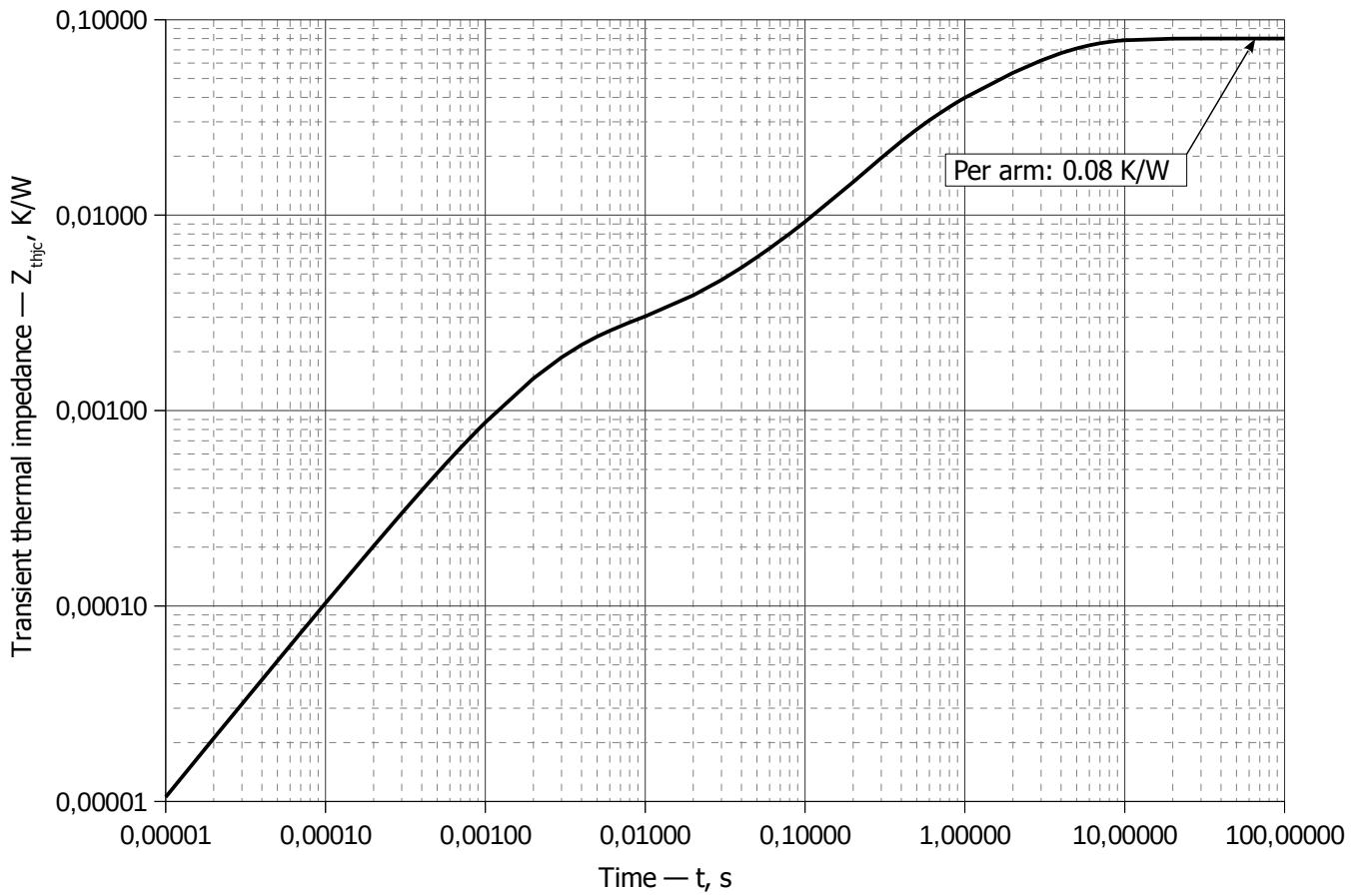
**Fig 1 – On-state characteristics of Limit device**

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	$T_j = 25^\circ\text{C}$	$T_j = T_{j,\max}$
<b>A</b>	0.86800379	0.93018191
<b>B</b>	0.00098693	0.00059893
<b>C</b>	0.01484991	0.00857857
<b>D</b>	0.00220103	0.00764154

**On-state characteristic model (see Fig. 1)**



**Fig 2 – Transient thermal impedance  $Z_{thjc}$  vs. time  $t$**

Analytical function for Transient thermal impedance junction to case  $Z_{thjc}$  for DC:

$$Z_{thjc} = \sum_{i=1}^n R_i \left( 1 - e^{-\frac{t}{\tau_i}} \right)$$

Where  $i = 1$  to  $n$ ,  $n$  is the number of terms in the series.

$t$  = Duration of heating pulse in seconds.

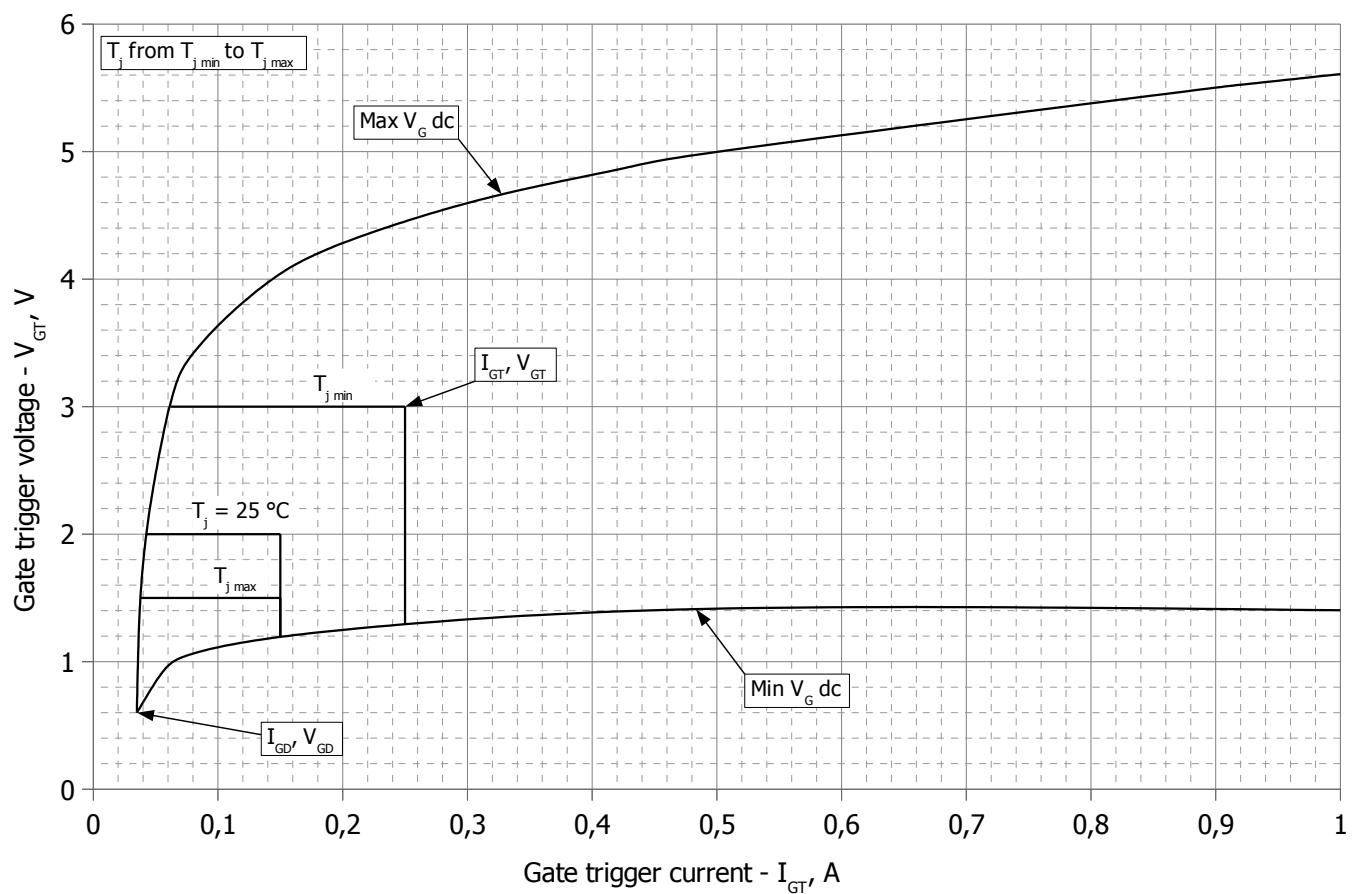
$Z_{thjc}$  = Thermal resistance at time  $t$ .

$R_i$  = Amplitude of  $p_{th}$  term.

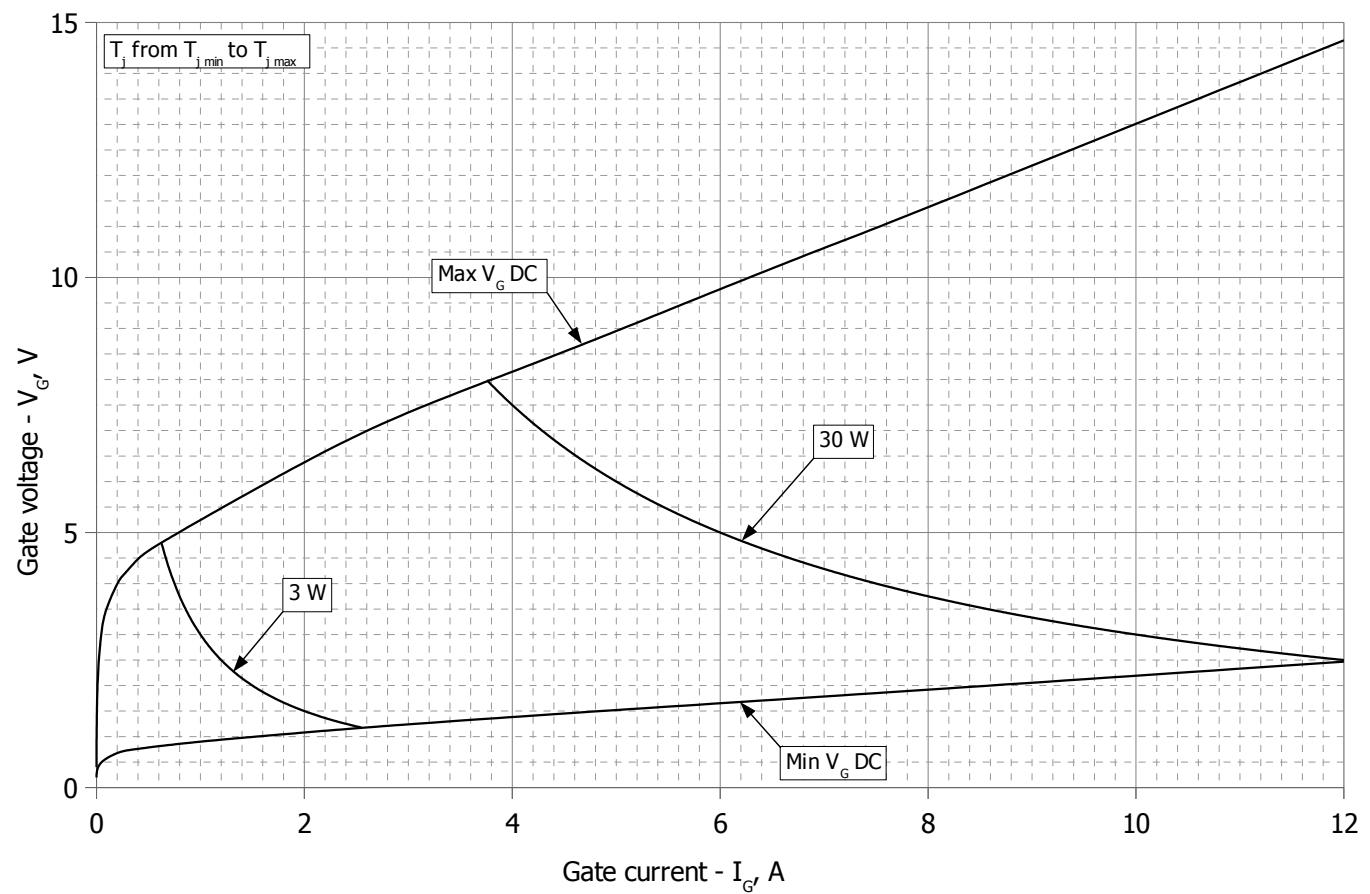
$\tau_i$  = Time constant of  $r_{th}$  term.

i	1	2	3	4	5	6
$R_i$ , K/W	0.0507	0.007806	0.02226	-0.007688	0.00471	0.00217
$\tau_i$ , s	2.801	1.283	0.3281	0.09408	0.0572	0.002255

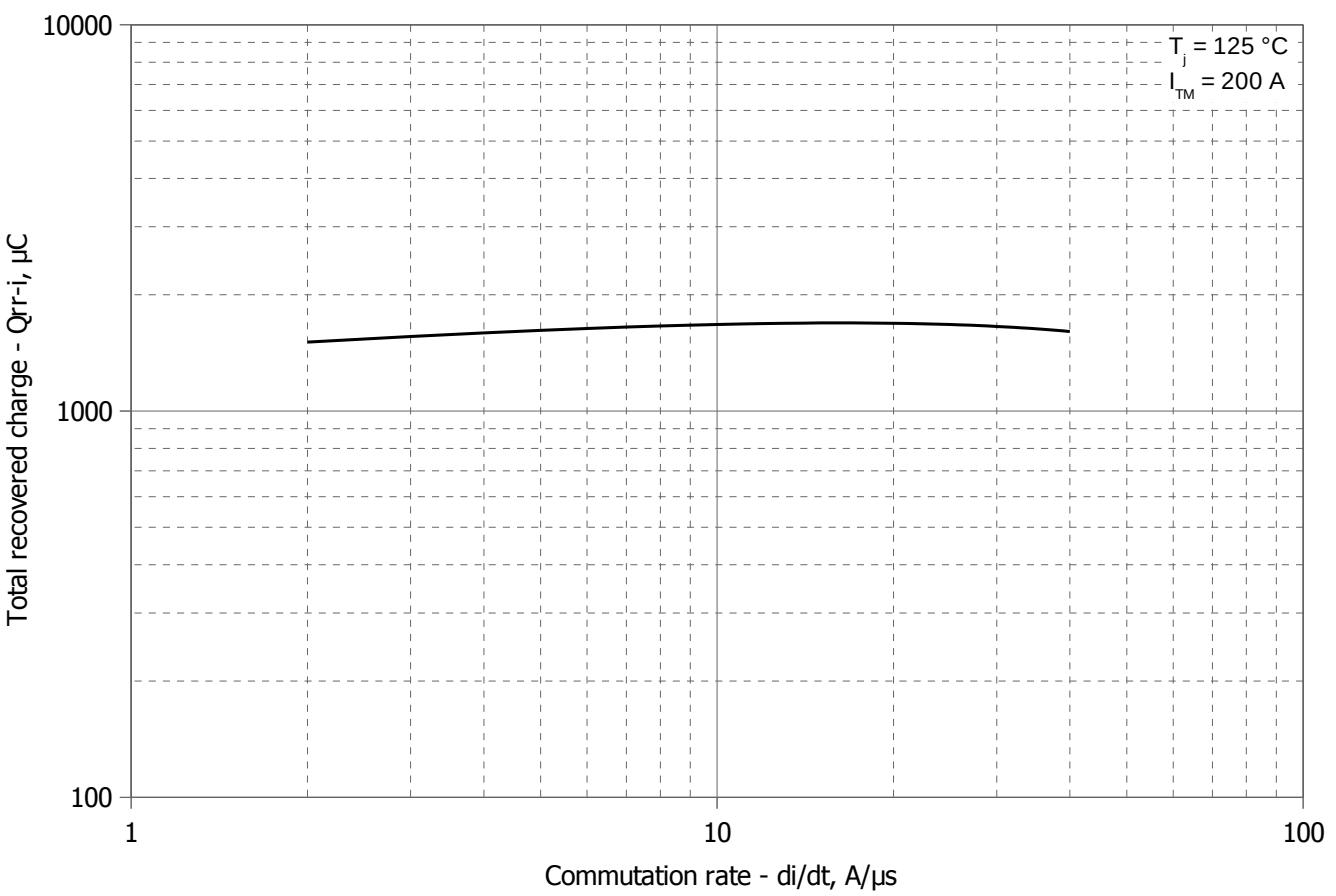
**Transient thermal impedance junction to case  $Z_{thjc}$  model (see Fig. 2)**



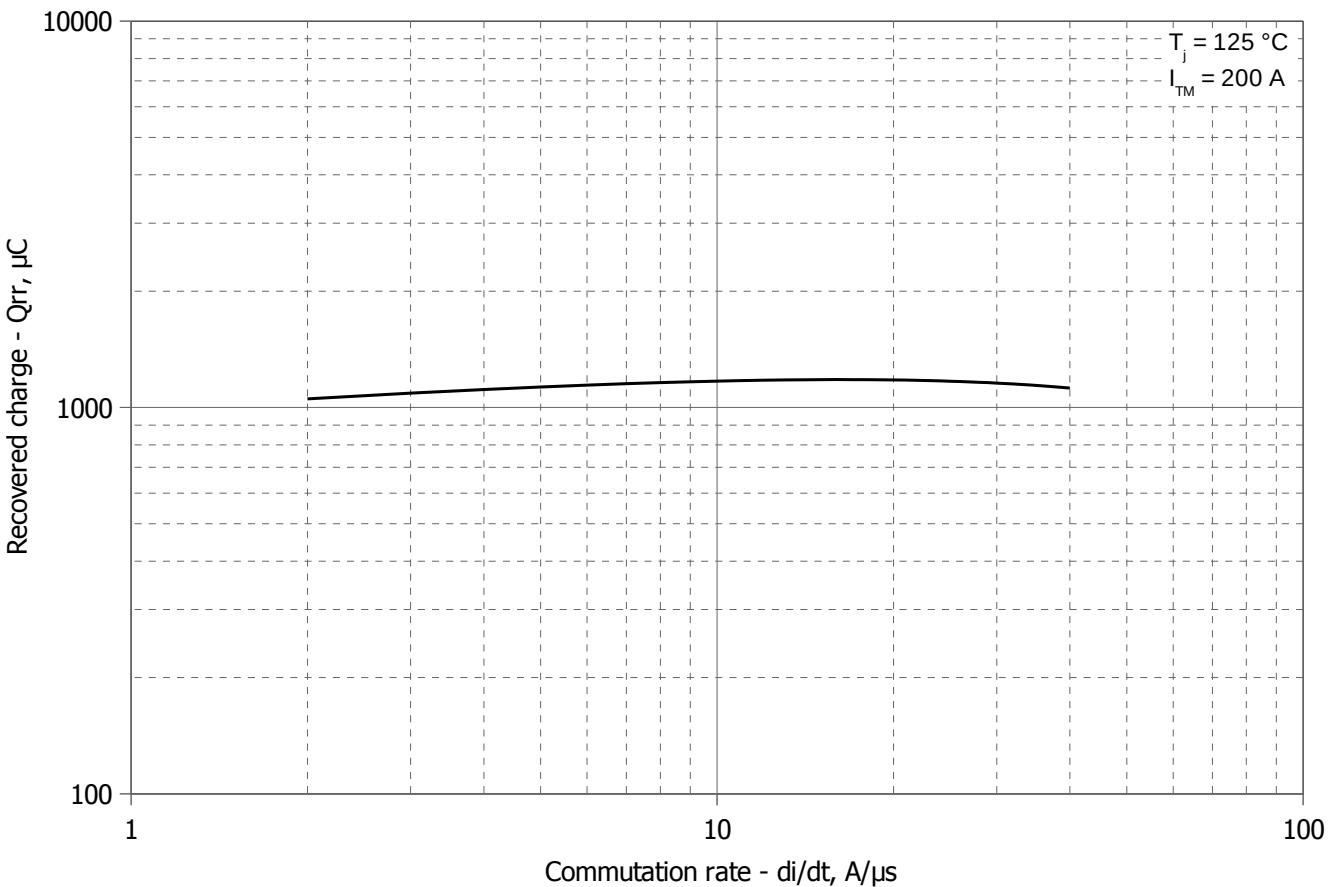
**Fig 3 – Gate characteristics – Trigger limits**



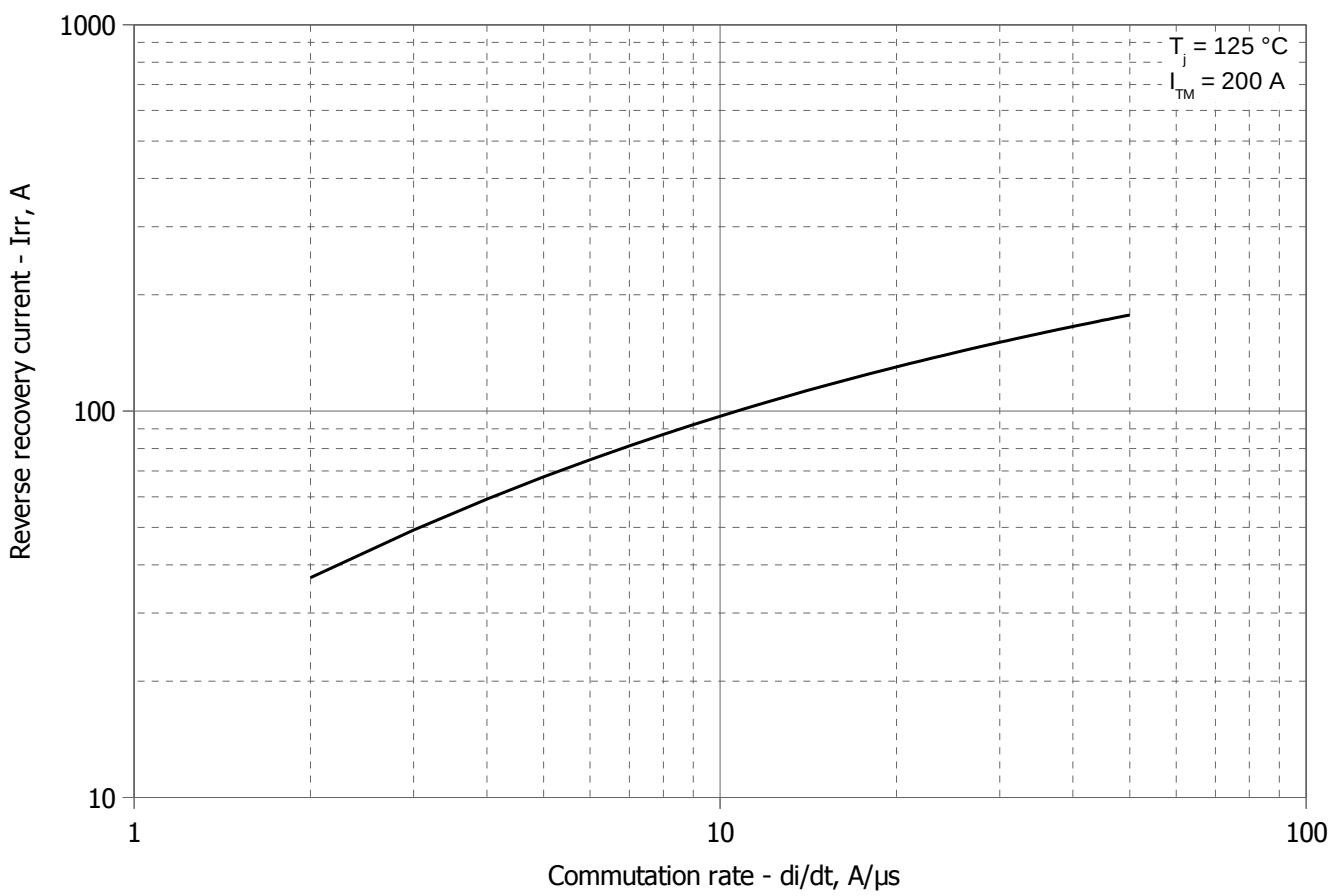
**Fig 4 - Gate characteristics – Power curves**



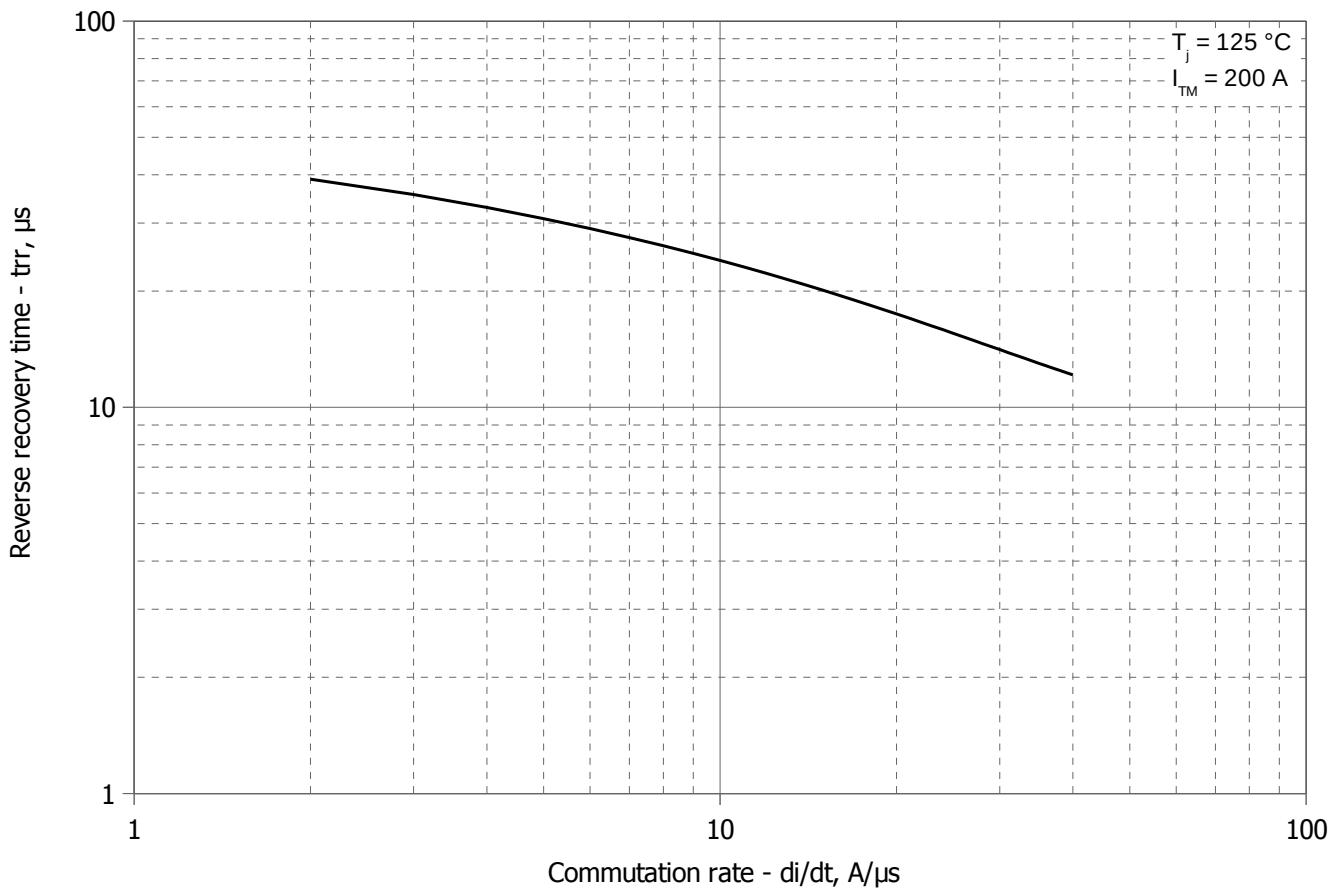
**Fig 5 – Maximum recovered charge  $Q_{rr-i}$  (integral) vs. commutation rate  $di_R/dt$**



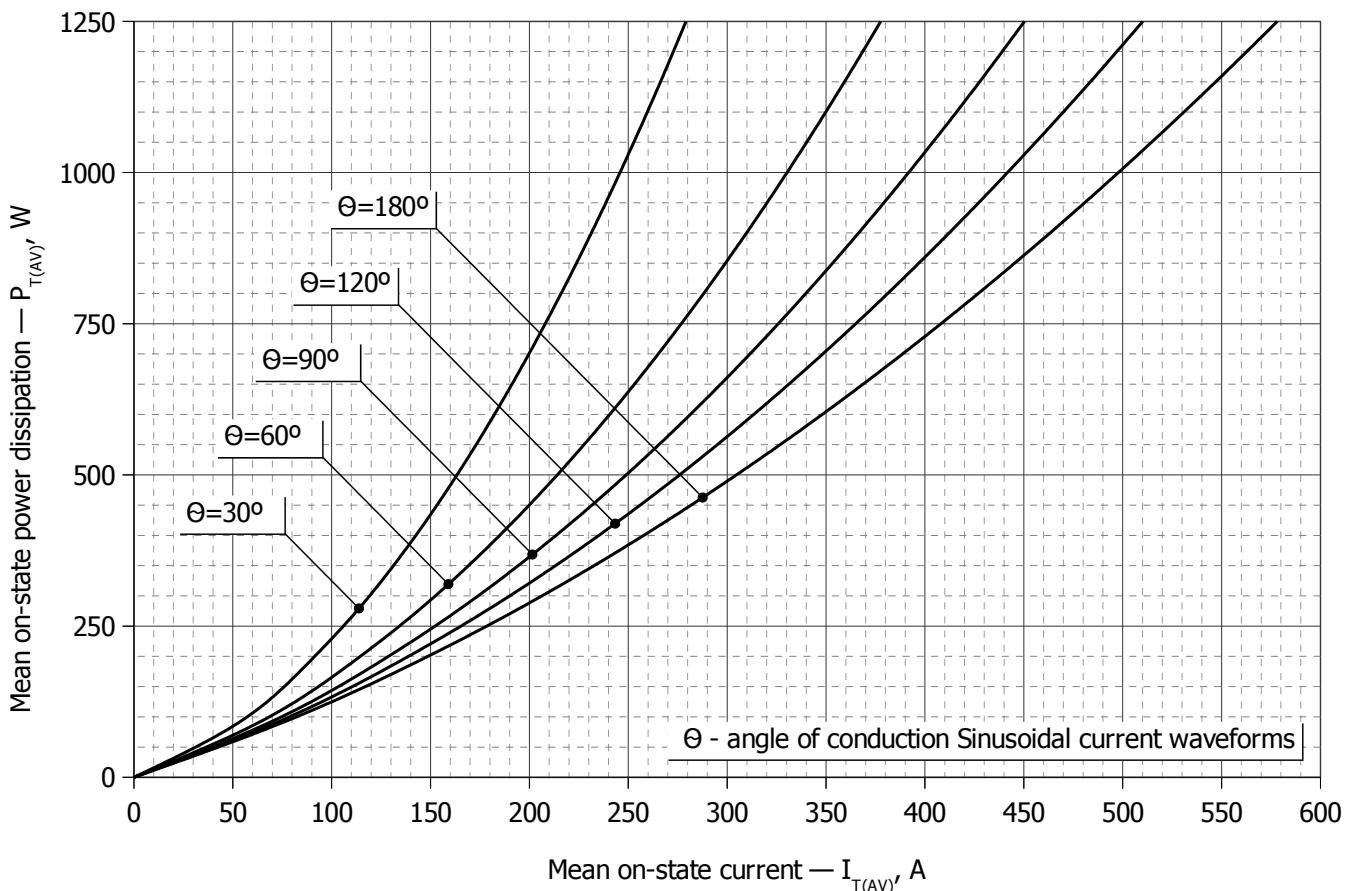
**Fig 6 – Maximum recovered charge  $Q_{rr}$  vs. commutation rate  $di_R/dt$  (25% chord)**



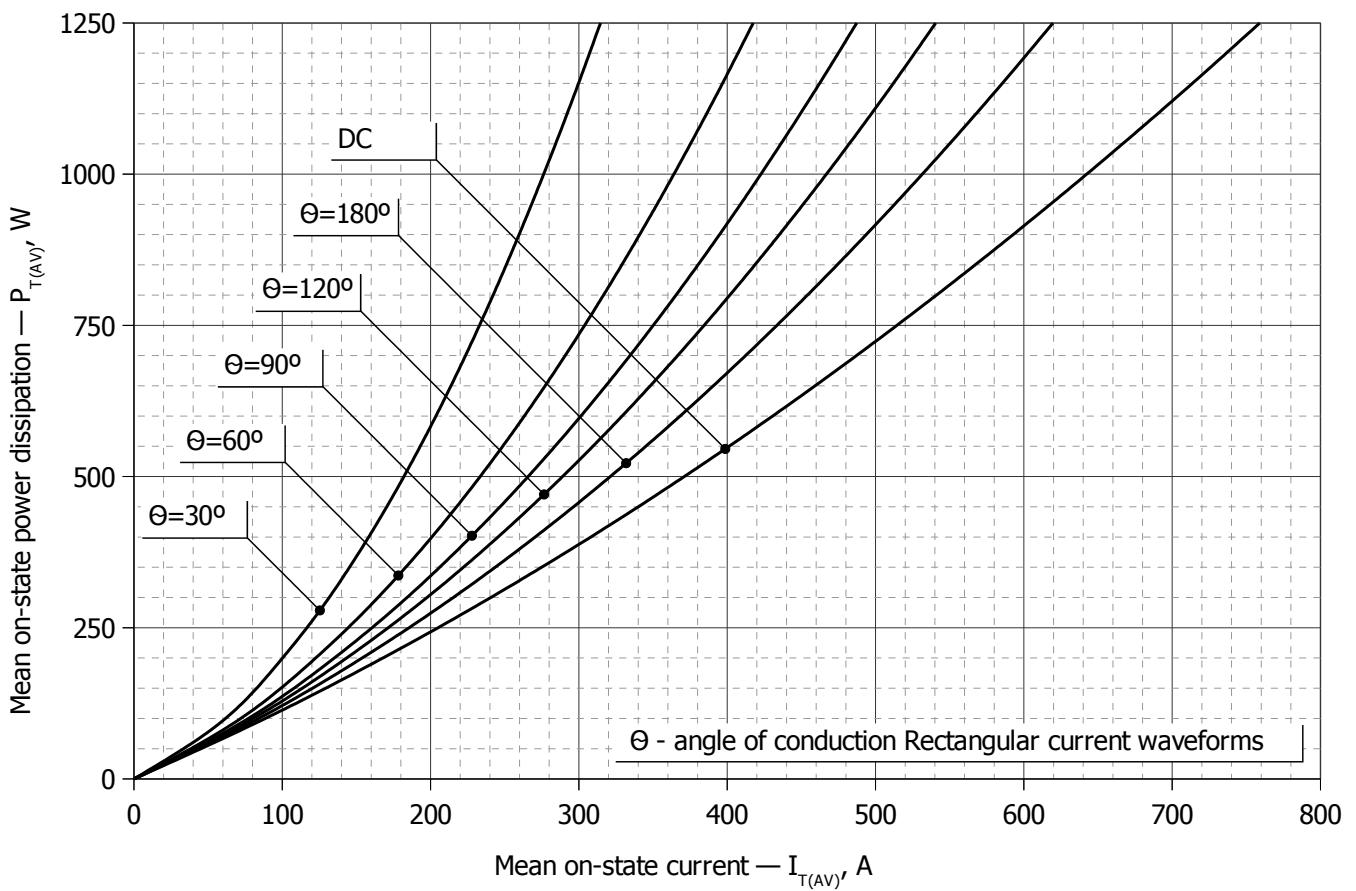
**Fig 7 – Maximum reverse recovery current  $I_{rr}$  vs. commutation rate  $di_r/dt$**



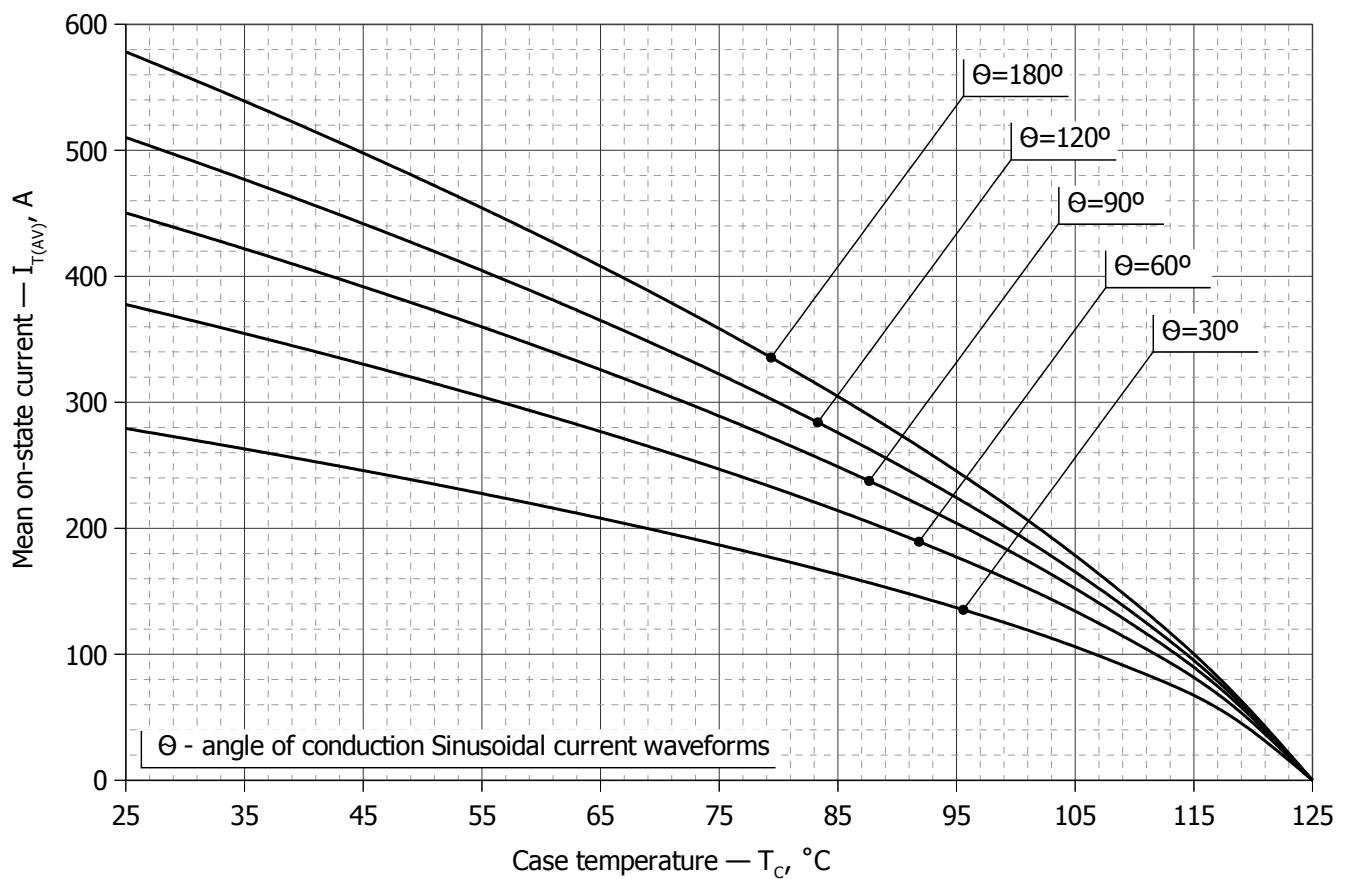
**Fig 8 – Maximum recovery time  $t_{rr}$  vs. commutation rate  $di_r/dt$  (25% chord)**



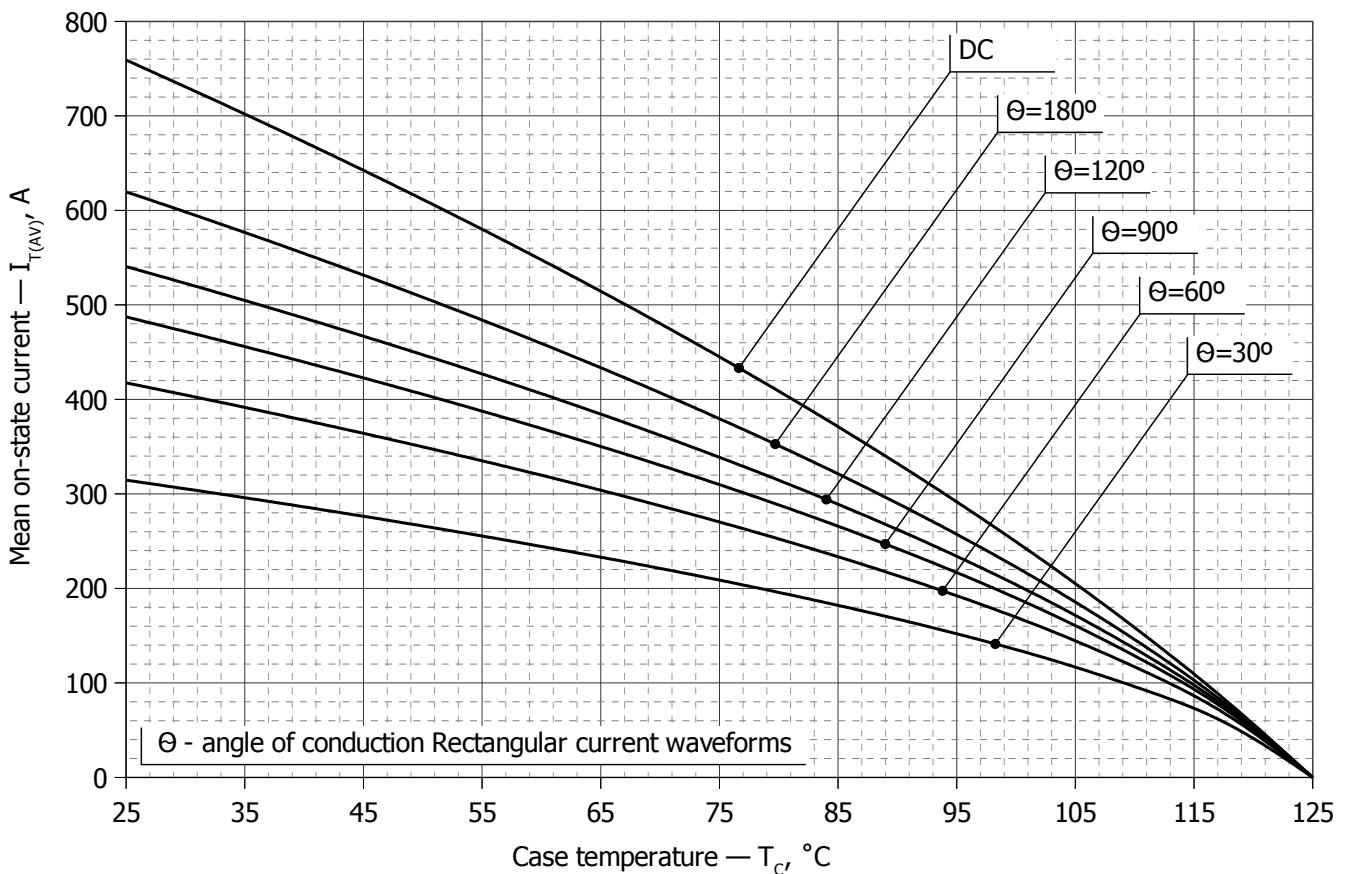
**Fig. 9 - Mean on-state power dissipation  $P_{TAV}$  vs. mean on-state current  $I_{TAV}$  for sinusoidal current waveforms at different conduction angles (f=50Hz, DSC)**



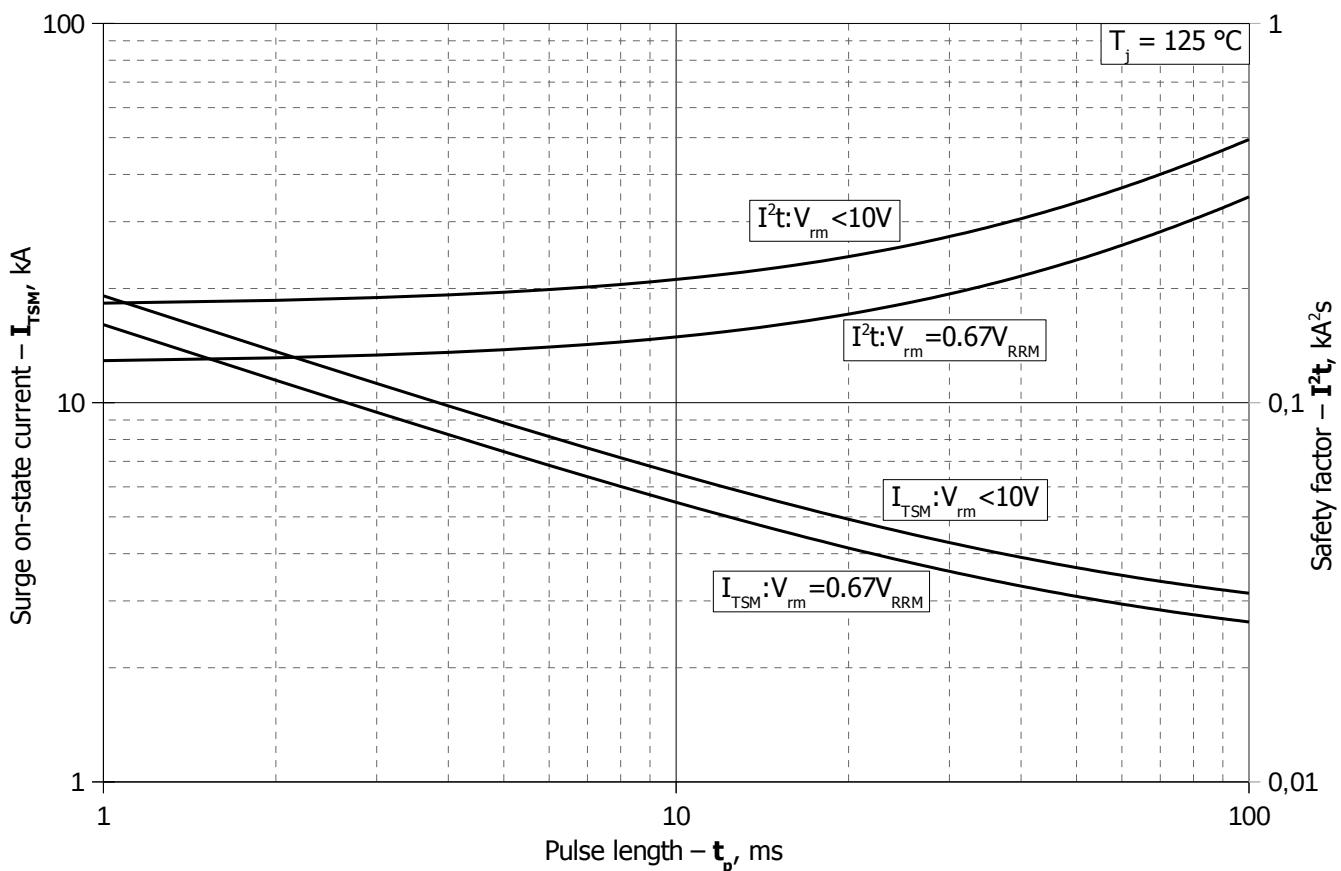
**Fig. 10 – Mean on-state power dissipation  $P_{TAV}$  vs. mean on-state current  $I_{TAV}$  for rectangular current waveforms at different conduction angles and for DC (f=50Hz, DSC)**



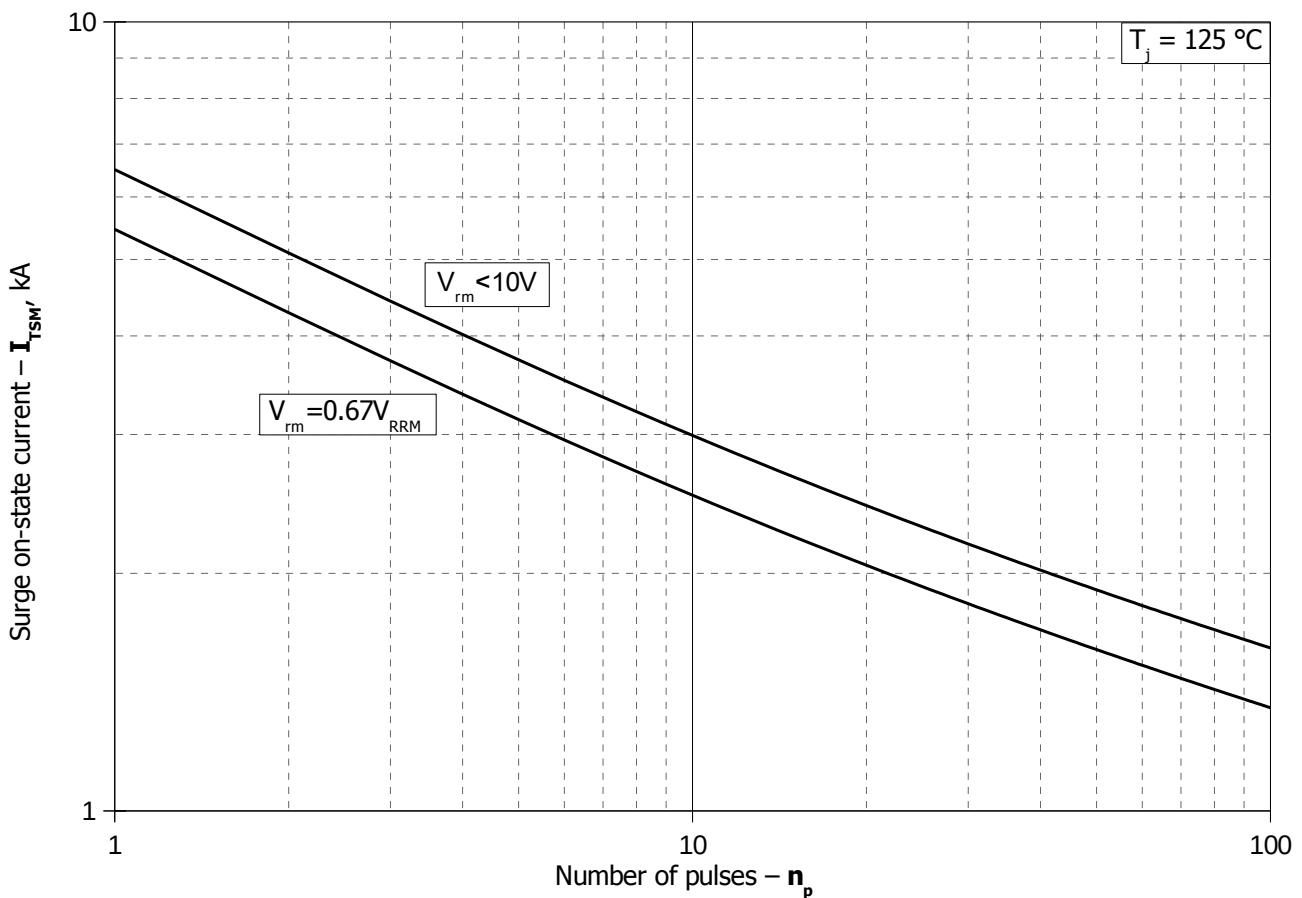
**Fig. 11 – Mean on-state current  $I_{TAV}$  vs. case temperature  $T_c$  for sinusoidal current waveforms at different conduction angles ( $f=50\text{Hz}$ , DSC)**



**Fig. 12 - Mean on-state current  $I_{TAV}$  vs. case temperature  $T_c$  for rectangular current waveforms at different conduction angles and for DC ( $f=50\text{Hz}$ , DSC)**



**Fig. 13 – Maximum surge on-state current  $I_{TSM}$  and safety factor  $I^2t$  vs. pulse length  $t_p$**



**Fig. 14 - Maximum surge on-state current  $I_{TSM}$  vs. number of pulses  $n_p$**